

Atomic Force Microscopy (AFM) - Workshop

Academia Sinica - RCAS

October 2nd, 2018

Fundamentals, Forces, and Ferroelectrics

This year marks the 32nd anniversary of the invention of the Atomic Force Microscope (AFM) by Binnig, Quate, and Gerber in 1986. From the simple beginnings of imaging surface structure, the AFM has evolved into an advanced characterization instrument, capable of measuring and mapping a wide range of materials properties.

Asylum Research, an Oxford Instruments Company, in collaboration with the Research Center for Applied Sciences (RCAS), will hold a workshop on AFM fundamentals and Advanced Applications on October 2nd, 2018. See below for the technical program. Lunch will be provided

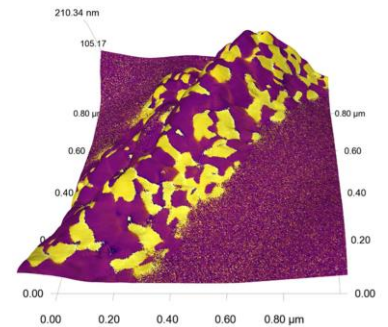
Where:

Lectures: B106 Auditorium, 1st Floor, IRBST, Academia Sinica

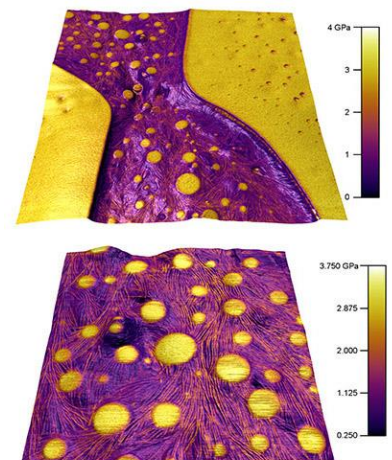
Demonstration: AFM lab, 6th Floor, IRBST, Academia Sinica

Workshop Agenda:

Time	Activity	Speaker
8:30 – 9:00	Registration	
9:00 – 9:10	Welcome!	<i>Deputy Director Prof. Chih-Wei CHU</i>
9:10 – 9:20	Introduction – Asylum Research	<i>Dr. David BECK</i>
9:20 – 10:00	AFM Fundamentals	<i>Dr. Qi ZHANG</i>
10:00 – 10:40	Nanomechanics	<i>Dr. Yukinori TANIGUCHI</i>
10:40 – 10:50	BREAK	
10:50 – 11:40	Piezoresponse Force Microscopy	<i>Dr. Qi ZHANG</i>
11:40 – 12:00	Domain Switching Kinetics and Relaxation of Transparent and Flexible Ferroelectric	<i>Dr. Pao-Wen SHAO</i>
12:00 – 1:00	LUNCH	
1:00 – 3:00	PFM Demonstration	
3:00 – 5:00	Nanomechanics Demonstration	



PFM Dual Amplitude Resonance Tracking (DART) Phase Image of Multiferroic BiFeO₃ Nanofibers - Courtesy of Jiangyu LI, University of Washington, USA.



AM-FM viscoelastic modulus mapping of polystyrene (PS) / polycaprolactone (PCL) polymer thin film. Imaged using blueDrive on a Cypher S at 2 Hz.

Registration – FREE (Deadline: Monday, October 1 by 4pm)

Just send your contact information to: David.Beck@Oxinst.com

